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INFORMATION DISCLOSURE STATEMENT BY APPLICANT <small>(use as many sheets as necessary)</small>				Application Number	09/767,647	
				Filing Date	1/22/01	
				First Named Inventor:	Rising III.	
				Group Art Unit	2621	
				Examiner Name	Sherali, I.	
Sheet 1	MAR 26 2004	of		Attorney Docket Number	80398.P341	
U.S. PATENT DOCUMENTS						
Exam. Initial*	Cite No. ¹	Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number known	Kind Code ² (If known)			
15		5,414,804	A	McWaid	5/9/95	382/245
15		5,953,452	A	Boone, et al.	9/14/99	382/199
15		5,686,961	A	Gasztanyi, et al.	11/11/97	375/240.01
15		6,223,195	B1	Tomomura	4/24/01	708/1402
15		6,259,396	B1	Pham, et al.	7/10/01	342/90
15		6,208,982	B1	Allen, Jr., et al.	3/27/01	706/11
15		6,560,586	B1	Liang, et al.	5/6/03	385/156 706/25
15		5,311,600		Aghajan, et al.	5/10/94	382/156
15		5,687,364		Saund, et al.	11/11/97	704/15
15		5,677,609		Khan, et al.	10/14/97	318/561
15		6,016,190		Glazman	1/18/00	356/43
15		5,329,478		Kirk, et al.	7/12/94	708/822
15		5,960,055		Samarasekera, et al.	9/28/99	378/14
15		5,953,388		Walnut, et al.	9/14/99	378/14
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FOREIGN PATENT DOCUMENTS								
Exam. Initial*	Cite No. ¹	Foreign Patent Document			Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	To
		Office ³	Number ⁴	Kind Code ⁵ (If known)				

Examiner Signature	<i>phila</i>	Date Considered	6/04
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¹Unique citation designation number. ²See attached Kinds of U.S. Patent Documents. ³Enter Office that issued the document, by the two-letter code (WIPO Standard S.3). ⁴For Japanese patent documents, the indication of the year of reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶Applicant is to place a check mark here if English language Translation is attached.

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		Examiner Name	Sherali, I.
		Attorney Docket Number	80398.P341

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OTHER ART - NO PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	T ²
ls		Sahiner, et al., "Iterative Inversion of the Radon Transform: Using Image-Adaptive Wavelet Constraints to Improve Image Reconstructions", IEEE Engineering in Medicine and Biology, Sept. 1996, Vol.15, Iss 5, pp.112-117.	
ls		Calzone, et al., "Video Compression by Means-Corrected Motion Compensation of Partial Quadrees", IEEE Transactions on Circuits and Systems for Video Technology, Vol.7, No.1, Feb.1997, pp.86-96.	
ls		Hsung, et al. "The Wavelet Transform of Higher Dimension and the Radon Transform", 1995 International Conference on Acoustics, Speech and Signal Processing, May 1995, Vol.2, pp.1113-1116.	
ls		Warrick, et al., "A Wavelet Localized Radon Transform Based Detector for a Signal with Unknown Parameters", 1995 Conference Record of the 29 th Asilomar Conference on Signals, Systems and Computers", Oct. 1995, Vol.2, pp.860-866.	
ls		Warrick, et al., "Detection of Linear Features Using a Localized Radon Transform with a Wavelet Filter", 1997 IEEE Intl. Conference of Acoustics, Speech and Signal Processing, April 1997, Vol.4, pp.2769-2772.	
ls		Rashid-Farrokhi, et al., "Localized Wavelet Based Computerized Tomography", Proceedings of the Intl. Conference on Image Processing, Oct.1995, Vol.2, pp.445-448.	
ls		Meir, et al., "Stochastic Approximation by Neural Networks Using the Radon and Wavelet Transforms", Proceedings of the 1998 IEEE Signal Processing Society Workshop, Aug.1998, pp.224-233.	
ls		Rashid-Farrokhi, et al., "Wavelet-Based Multiresolution Local Tomography", IEEE Transactions on Image Processing, Vol.6, No.10, Oct.1997, pp.1412-1430.	
ls		Destefano, et al., "Wavelet Localization of the Radon Transform in Even Dimensions", Proceedings of the IEEE-SP International Symposium on Time-Frequency and Time-Scale Analysis, Oct.1992, pp.137-140.	
ls		Olson, et al., "Wavelet Localization of the Radon Transform", IEEE Transactions on Signal Processing, Vol.42, No.8, Aug.1994, pp.2055-2067.	
ls		Sahiner, et al., "Iterative Inversion of the Radon Transform using Image-Adaptive Wavelet Constraints", Proceedings of the 1998 International Conference on Image Processing, Oct.1998, Vol.2, pp.709-713.	
ls		Takizawa, et al., "Ultrasonic Tomography using Arc Focusing Beam", 1998 IEEE Ultrasonics Symposium, Oct.1998, Vol.2, pp.1659-1662.	

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Substitute for Form 1449A/PTO (Modified) <h2 style="text-align: center;">INFORMATION DISCLOSURE STATEMENT BY APPLICANT</h2> <p style="text-align: center;">(use as many sheets as necessary)</p>		<div style="text-align: right; font-weight: bold;">Complete if Known</div> <table border="1" style="width: 100%; border-collapse: collapse;"> <tr> <td style="width: 50%;">Application Number</td> <td style="width: 50%;">09/767,647</td> </tr> <tr> <td>Filing Date</td> <td>1/22/01</td> </tr> <tr> <td>First Named Inventor:</td> <td>Rising III.</td> </tr> <tr> <td>Group Art Unit</td> <td>2621</td> </tr> <tr> <td>Examiner Name</td> <td>Sherali, I.</td> </tr> <tr> <td>Attorney Docket Number</td> <td>80398.P341</td> </tr> </table>		Application Number	09/767,647	Filing Date	1/22/01	First Named Inventor:	Rising III.	Group Art Unit	2621	Examiner Name	Sherali, I.	Attorney Docket Number	80398.P341
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OTHER ART - NO PATENT LITERATURE DOCUMENTS															
Examiner Initials*	Cite No ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	T ²												
15		Sahiner, et al., "On the Use of Wavelets in Inverting the Radon Transform", Conference Record of the 1992 IEEE Nuclear Science Symposium and Medical Imaging Conference, Oct. 1992, Vol.2, pp.1129-1131.													
15		Rodenas, et al., "A New Automatic Internal Wave Detection and Characterization Method for SAR Images", OCEANS '98 Conference Proceedings, Sept. 1998, Vol.2, pp.613-618.													
15		Sahiner, et al., "Iterative Inversion of the Radon Transform Using Image-Adaptive Wavelet Constraints", 18 th Annual Intl. conference of the IEEE Engineering in Medicine and Biology Society, Oct. 1996, Vol.2, pp.772-723.													
15		Lu, et al., "Directional Noise Removal from Aerial Imagery using Wavelet X-Ray Transform", 1998 IEEE International Geoscience and Remote Sensing Symposium Proceedings, Vol.4, July 1998, pp.2038-2040.													
15		Magli, et al., "A Pattern Detection and Compression Algorithm Based on the Joint Wavelet and Radon Transform", 13 th Intl. Conference on Digital Signal Processing, July 1997, Vol.2, pp.559-562.													
15		Rising, "Inversion Processed in the Human Visual System", vol.3959 (6/2000), Sony MediaSoft Labs, US. Research Labs, San Jose, CA, pp.400-410.													
15		Albanesi, "Thresholding Wavelets for Image Compression", 1998, IEEE, University of Pavia, Dipartimento di Informatica e Sistemistica, pp.374-389.													
15		Ahmed, et al., "Application of Multi-layer Neural Networks to Image Compression", 1997 IEEE, International Symposium on Circuits and Systems, June 9-12, 1997 Hong Kong, pp.1273-1276.													
15		Carroll, et al., "Construction of Neural Nets Using the Radon Transform", Department of Electrical Engineering Princeton University, IJCNN International Joint Conference on Neural Networks, June 19-22, 1998, p.607-611.													
15		Khuwaja, et al., "Fingerprint Image Compression", Physics Department, Kuwait University, IEEE, pp.517-526													
15		Fanghanel, et al., "Optimizing Wavelet Transform Coding Using a Neural Network", 1997 IEEE, Universitat der Bundeswehr Hamburg, pp.1341-1343.													

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Filing Date	1/22/2001
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Art Unit	2621
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Examiner Name	Sherali, Ishrat I.
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Attorney Docket Number	080398.P341
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